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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	276480
Number of I/O	280
Number of Gates	1500000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	484-BGA
Supplier Device Package	484-FPBGA (23x23)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a3pe1500-fg484i

Table 2-4 • Overshoot and Undershoot Limits¹

VCCI and VMV	Average VCCI–GND Overshoot or Undershoot Duration as a Percentage of Clock Cycle ²	Maximum Overshoot/Undershoot ²
2.7 V or less	10%	1.4 V
	5%	1.49 V
3 V	10%	1.1 V
	5%	1.19 V
3.3 V	10%	0.79 V
	5%	0.88 V
3.6 V	10%	0.45 V
	5%	0.54 V

Notes:

1. Based on reliability requirements at 85°C.
2. The duration is allowed at one out of six clock cycles. If the overshoot/undershoot occurs at one out of two cycles, the maximum overshoot/undershoot has to be reduced by 0.15 V.
3. This table does not provide PCI overshoot/undershoot limits.

I/O Power-Up and Supply Voltage Thresholds for Power-On Reset (Commercial and Industrial)

Sophisticated power-up management circuitry is designed into every ProASIC[®]3E device. These circuits ensure easy transition from the powered-off state to the powered-up state of the device. The many different supplies can power up in any sequence with minimized current spikes or surges. In addition, the I/O will be in a known state through the power-up sequence. The basic principle is shown in [Figure 2-1 on page 2-4](#).

There are five regions to consider during power-up.

ProASIC3E I/Os are activated only if ALL of the following three conditions are met:

1. VCC and VCCI are above the minimum specified trip points ([Figure 2-1 on page 2-4](#)).
2. VCCI > VCC – 0.75 V (typical)
3. Chip is in the operating mode.

VCCI Trip Point:

Ramping up: 0.6 V < trip_point_up < 1.2 V

Ramping down: 0.5 V < trip_point_down < 1.1 V

VCC Trip Point:

Ramping up: 0.6 V < trip_point_up < 1.1 V

Ramping down: 0.5 V < trip_point_down < 1 V

VCC and VCCI ramp-up trip points are about 100 mV higher than ramp-down trip points. This specifically built-in hysteresis prevents undesirable power-up oscillations and current surges. Note the following:

- During programming, I/Os become tristated and weakly pulled up to VCCI.
- JTAG supply, PLL power supplies, and charge pump VPUMP supply have no influence on I/O behavior.

Table 2-8 • Summary of I/O Input Buffer Power (per pin) – Default I/O Software Settings (continued)

	VMV (V)	Static Power PDC2 (mW) ¹	Dynamic Power PAC9 (μW/MHz) ²
HSTL (I)	1.5	0.17	2.03
HSTL (II)	1.5	0.17	2.03
SSTL2 (I)	2.5	1.38	4.48
SSTL2 (II)	2.5	1.38	4.48
SSTL3 (I)	3.3	3.21	9.26
SSTL3 (II)	3.3	3.21	9.26
Differential			
LVDS/B-LVDS/M-LVDS	2.5	2.26	1.50
LVPECL	3.3	5.71	2.17

Notes:

1. PDC2 is the static power (where applicable) measured on VMV.
2. PAC9 is the total dynamic power measured on VCC and VMV.
3. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD8b specification.

Table 2-9 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings ¹

	C _{LOAD} (pF)	VCCI (V)	Static Power PDC3 (mW) ²	Dynamic Power PAC10 (μW/MHz) ³
Single-Ended				
3.3 V LVTTTL/LVCMOS	35	3.3	–	474.70
3.3 V LVTTTL/LVCMOS Wide Range ⁴	35	3.3	–	474.70
2.5 V LVCMOS	35	2.5	–	270.73
1.8 V LVCMOS	35	1.8	–	151.78
1.5 V LVCMOS (JESD8-11)	35	1.5	–	104.55
3.3 V PCI	10	3.3	–	204.61
3.3 V PCI-X	10	3.3	–	204.61
Voltage-Referenced				
3.3 V GTL	10	3.3	–	24.08
2.5 V GTL	10	2.5	–	13.52
3.3 V GTL+	10	3.3	–	24.10
2.5 V GTL+	10	2.5	–	13.54
HSTL (I)	20	1.5	7.08	26.22
HSTL (II)	20	1.5	13.88	27.22
SSTL2 (I)	30	2.5	16.69	105.56
SSTL2 (II)	30	2.5	25.91	116.60

Notes:

1. Dynamic power consumption is given for standard load and software default drive strength and output slew.
2. PDC3 is the static power (where applicable) measured on VCCI.
3. PAC10 is the total dynamic power measured on VCC and VCCI.
4. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range as specified in the JESD8-B specification.

Combinatorial Cells Contribution— P_{C-CELL}

$$P_{C-CELL} = N_{C-CELL} * \alpha_1 / 2 * PAC7 * F_{CLK}$$

N_{C-CELL} is the number of VersaTiles used as combinatorial modules in the design.

α_1 is the toggle rate of VersaTile outputs—guidelines are provided in [Table 2-11 on page 2-11](#).

F_{CLK} is the global clock signal frequency.

Routing Net Contribution— P_{NET}

$$P_{NET} = (N_{S-CELL} + N_{C-CELL}) * \alpha_1 / 2 * PAC8 * F_{CLK}$$

N_{S-CELL} is the number of VersaTiles used as sequential modules in the design.

N_{C-CELL} is the number of VersaTiles used as combinatorial modules in the design.

α_1 is the toggle rate of VersaTile outputs—guidelines are provided in [Table 2-11 on page 2-11](#).

F_{CLK} is the global clock signal frequency.

I/O Input Buffer Contribution— P_{INPUTS}

$$P_{INPUTS} = N_{INPUTS} * \alpha_2 / 2 * PAC9 * F_{CLK}$$

N_{INPUTS} is the number of I/O input buffers used in the design.

α_2 is the I/O buffer toggle rate—guidelines are provided in [Table 2-11 on page 2-11](#).

F_{CLK} is the global clock signal frequency.

I/O Output Buffer Contribution— $P_{OUTPUTS}$

$$P_{OUTPUTS} = N_{OUTPUTS} * \alpha_2 / 2 * \beta_1 * PAC10 * F_{CLK}$$

$N_{OUTPUTS}$ is the number of I/O output buffers used in the design.

α_2 is the I/O buffer toggle rate—guidelines are provided in [Table 2-11 on page 2-11](#).

β_1 is the I/O buffer enable rate—guidelines are provided in [Table 2-12 on page 2-11](#).

F_{CLK} is the global clock signal frequency.

RAM Contribution— P_{MEMORY}

$$P_{MEMORY} = PAC11 * N_{BLOCKS} * F_{READ-CLOCK} * \beta_2 + PAC12 * N_{BLOCK} * F_{WRITE-CLOCK} * \beta_3$$

N_{BLOCKS} is the number of RAM blocks used in the design.

$F_{READ-CLOCK}$ is the memory read clock frequency.

β_2 is the RAM enable rate for read operations—guidelines are provided in [Table 2-12 on page 2-11](#).

$F_{WRITE-CLOCK}$ is the memory write clock frequency.

β_3 is the RAM enable rate for write operations—guidelines are provided in [Table 2-12 on page 2-11](#).

PLL Contribution— P_{PLL}

$$P_{PLL} = PAC13 + PAC14 * F_{CLKOUT}$$

F_{CLKOUT} is the output clock frequency.¹

1. The PLL dynamic contribution depends on the input clock frequency, the number of output clock signals generated by the PLL, and the frequency of each output clock. If a PLL is used to generate more than one output clock, include each output clock in the formula by adding its corresponding contribution ($PAC14 * F_{CLKOUT}$ product) to the total PLL contribution.

Overview of I/O Performance

Summary of I/O DC Input and Output Levels – Default I/O Software Settings

Table 2-13 • Summary of Maximum and Minimum DC Input and Output Levels
Applicable to Commercial and Industrial Conditions

I/O Standard	Drive Strength	Equivalent Software Default Drive Strength Option ¹	Slew Rate	VIL		VIH		VOL	VOH	IOL ³	IOH ³
				Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA
3.3 V LVTTTL / 3.3 V LVCMOS	12 mA	12 mA	High	–0.3	0.8	2	3.6	0.4	2.4	12	12
3.3 V LVCMOS Wide Range	100 μ A	12 mA	High	–0.3	0.8	2	3.6	0.2	VCCI – 0.2	0.1	0.1
2.5 V LVCMOS	12 mA	12 mA	High	–0.3	0.7	1.7	3.6	0.7	1.7	12	12
1.8 V LVCMOS	12 mA	12 mA	High	–0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI – 0.45	12	12
1.5 V LVCMOS	12 mA	12 mA	High	–0.3	0.30 * VCCI	0.7 * VCCI	3.6	0.25 * VCCI	0.75 * VCCI	12	12
3.3 V PCI	Per PCI Specification										
3.3 V PCI-X	Per PCI-X Specification										
3.3 V GTL	20 mA ²	20 mA ²	High	–0.3	VREF – 0.05	VREF + 0.05	3.6	0.4	–	20	20
2.5 V GTL	20 mA ²	20 mA ²	High	–0.3	VREF – 0.05	VREF + 0.05	3.6	0.4	–	20	20
3.3 V GTL+	35 mA	35 mA	High	–0.3	VREF – 0.1	VREF + 0.1	3.6	0.6	–	35	35
2.5 V GTL+	33 mA	33 mA	High	–0.3	VREF – 0.1	VREF + 0.1	3.6	0.6	–	33	33
HSTL (I)	8 mA	8 mA	High	–0.3	VREF – 0.1	VREF + 0.1	3.6	0.4	VCCI – 0.4	8	8
HSTL (II)	15 mA ²	15 mA ²	High	–0.3	VREF – 0.1	VREF + 0.1	3.6	0.4	VCCI – 0.4	15	15
SSTL2 (I)	15 mA	15 mA	High	–0.3	VREF – 0.2	VREF + 0.2	3.6	0.54	VCCI – 0.62	15	15
SSTL2 (II)	18 mA	18 mA	High	–0.3	VREF – 0.2	VREF + 0.2	3.6	0.35	VCCI – 0.43	18	18
SSTL3 (I)	14 mA	14 mA	High	–0.3	VREF – 0.2	VREF + 0.2	3.6	0.7	VCCI – 1.1	14	14
SSTL3 (II)	21 mA	21 mA	High	–0.3	VREF – 0.2	VREF + 0.2	3.6	0.5	VCCI – 0.9	21	21

Notes:

1. The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is $\pm 100 \mu$ A. Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
2. Output drive strength is below JEDEC specification.
3. Currents are measured at 85°C junction temperature.
4. Output Slew Rates can be extracted from [IBIS Models](http://www.microsemi.com/index.php?option=com_content&id=1671&lang=en&view=article), located at http://www.microsemi.com/index.php?option=com_content&id=1671&lang=en&view=article.

3.3 V LVCMOS Wide Range

Table 2-29 • Minimum and Maximum DC Input and Output Levels

3.3 V LVCMOS Wide Range	Equivalent Software Default Drive	VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL ²	IIH ³
Drive Strength	Strength Option ¹	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	μA	μA	Max. mA ⁴	Max. mA ⁴	μA ⁵	μA ⁵
100 μA	2 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	27	25	10	10
100 μA	4 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	27	25	10	10
100 μA	6 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	54	51	10	10
100 μA	8 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	54	51	10	10
100 μA	12 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	109	103	10	10
100 μA	16 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	127	132	10	10
100 μA	24 mA	−0.3	0.8	2	3.6	0.2	VDD − 0.2	100	100	181	268	10	10

Notes:

1. The minimum drive strength for any LVCMOS 3.3 V software configuration when run in wide range is ±100 μA. Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
2. IIL is the input leakage current per I/O pin over recommended operation conditions where −0.3 V < VIN < VIL.
3. IIH is the input leakage current per I/O pin over recommended operating conditions VIH < VIN < VCCI. Input current is larger when operating outside recommended ranges.
4. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
5. Currents are measured at 85°C junction temperature.
6. Software default selection highlighted in gray.

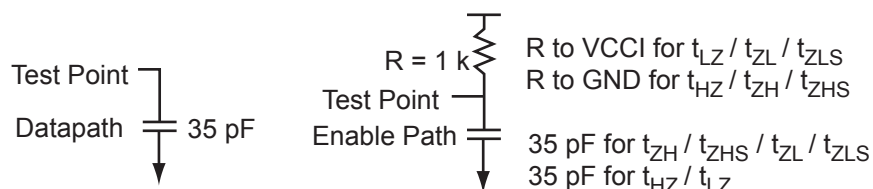


Figure 2-7 • AC Loading

Table 2-30 • 3.3 V LVCMOS Wide Range AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	C _{LOAD} (pF)
0	3.3	1.4	–	35

Note: *Measuring point = Vtrip. See [Table 2-15 on page 2-18](#) for a complete table of trip points.

SSTL3 Class I

Stub-Speed Terminated Logic for 3.3 V memory bus standard (JESD8-8). ProASIC3E devices support Class I. This provides a differential amplifier input buffer and a push-pull output buffer.

Table 2-72 • Minimum and Maximum DC Input and Output Levels

SSTL3 Class I	VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL	IIH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
14 mA	−0.3	VREF − 0.2	VREF + 0.2	3.6	0.7	VCCI − 1.1	14	14	54	51	10	10

Notes:

1. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
2. Currents are measured at 85°C junction temperature.

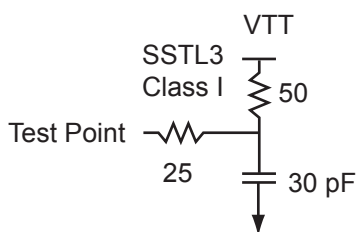


Figure 2-20 • AC Loading

Table 2-73 • AC Waveforms, Measuring Points, and Capacitive Loads

Input Low (V)	Input High (V)	Measuring Point* (V)	VREF (typ.) (V)	VTT (typ.) (V)	C _{LOAD} (pF)
VREF − 0.2	VREF + 0.2	1.5	1.5	1.485	30

Note: *Measuring point = Vtrip. See [Table 2-15 on page 2-18](#) for a complete table of trip points.

Timing Characteristics

Table 2-74 • SSTL3 Class I

Commercial-Case Conditions: T_J = 70°C, Worst-Case VCC = 1.425 V,
Worst-Case VCCI = 3.0 V, VREF = 1.5 V

Speed Grade	t _{DOUT}	t _{DP}	t _{DIN}	t _{PY}	t _{EOUT}	t _{ZL}	t _{ZH}	t _{LZ}	t _{HZ}	t _{ZLS}	t _{ZHS}	Units
Std.	0.66	2.31	0.04	1.25	0.43	2.35	1.84			4.59	4.07	ns
−1	0.56	1.96	0.04	1.06	0.36	2.00	1.56			3.90	3.46	ns
−2	0.49	1.72	0.03	0.93	0.32	1.75	1.37			3.42	3.04	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-5](#) for derating values.

Timing Characteristics

Table 2-80 • LVDS

Commercial-Case Conditions: $T_J = 70^\circ\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$, Worst-Case $V_{CCI} = 2.3\text{ V}$

Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	Units
Std.	0.66	1.87	0.04	1.82	ns
-1	0.56	1.59	0.04	1.55	ns
-2	0.49	1.40	0.03	1.36	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-5](#) for derating values.

B-LVDS/M-LVDS

Bus LVDS (B-LVDS) and Multipoint LVDS (M-LVDS) specifications extend the existing LVDS standard to high-performance multipoint bus applications. Multidrop and multipoint bus configurations may contain any combination of drivers, receivers, and transceivers. Microsemi LVDS drivers provide the higher drive current required by B-LVDS and M-LVDS to accommodate the loading. The drivers require series terminations for better signal quality and to control voltage swing. Termination is also required at both ends of the bus since the driver can be located anywhere on the bus. These configurations can be implemented using the TRIBUF_LVDS and BIBUF_LVDS macros along with appropriate terminations. Multipoint designs using Microsemi LVDS macros can achieve up to 200 MHz with a maximum of 20 loads. A sample application is given in [Figure 2-23](#). The input and output buffer delays are available in the LVDS section in [Table 2-80](#).

Example: For a bus consisting of 20 equidistant loads, the following terminations provide the required differential voltage, in worst-case Industrial operating conditions, at the farthest receiver: $R_S = 60\ \Omega$ and $R_T = 70\ \Omega$, given $Z_0 = 50\ \Omega$ (2") and $Z_{stub} = 50\ \Omega$ (~1.5").

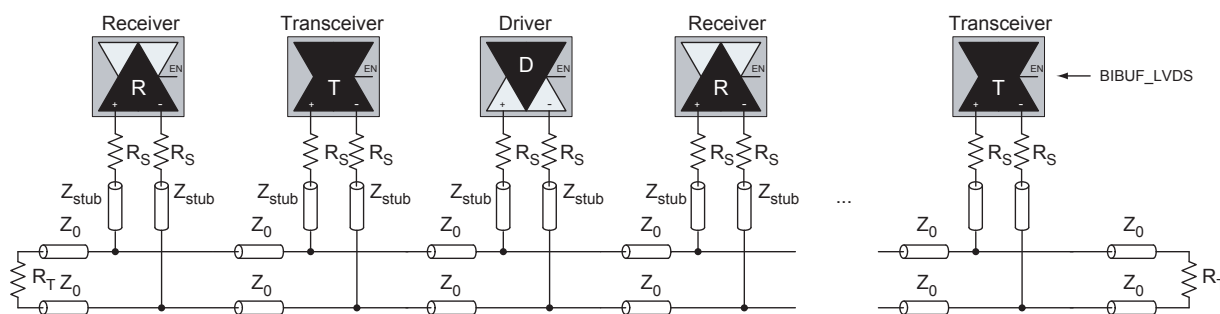


Figure 2-23 • B-LVDS/M-LVDS Multipoint Application Using LVDS I/O Buffers

Output DDR Module

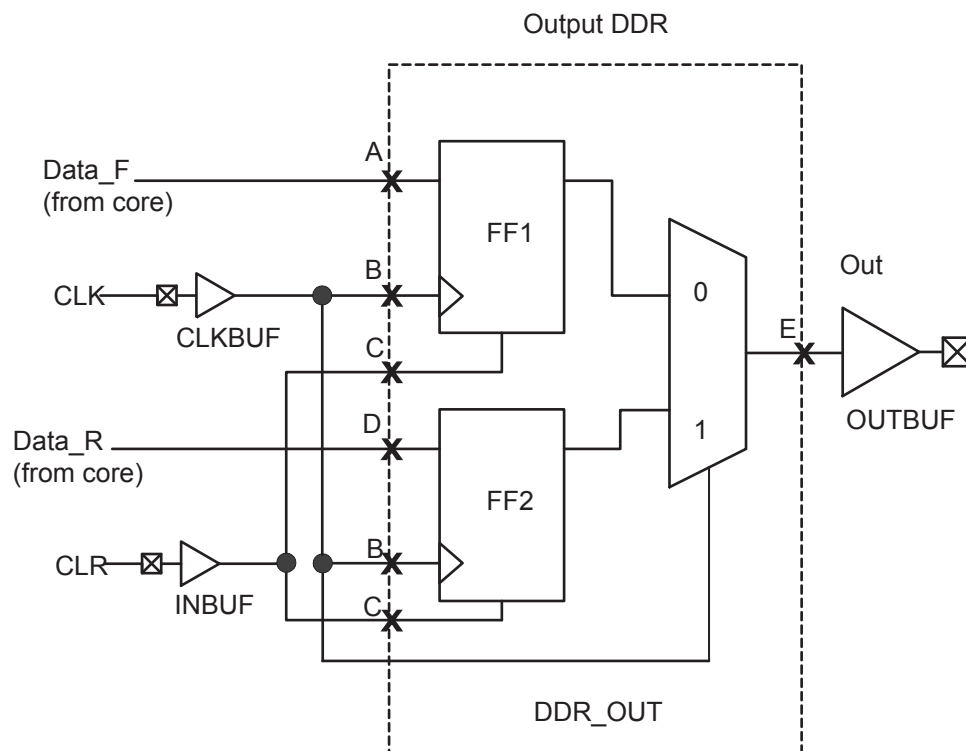


Figure 2-32 • Output DDR Timing Model

Table 2-91 • Parameter Definitions

Parameter Name	Parameter Definition	Measuring Nodes (from, to)
t_{DDROCLKQ}	Clock-to-Out	B, E
$t_{\text{DDROCLR2Q}}$	Asynchronous Clear-to-Out	C, E
$t_{\text{DDROREMCLR}}$	Clear Removal	C, B
$t_{\text{DDRORECCLR}}$	Clear Recovery	C, B
t_{DDROSUD1}	Data Setup Data_F	A, B
t_{DDROSUD2}	Data Setup Data_R	D, B
t_{DDROHD1}	Data Hold Data_F	A, B
t_{DDROHD2}	Data Hold Data_R	D, B

VersaTile Characteristics

VersaTile Specifications as a Combinatorial Module

The ProASIC3E library offers all combinations of LUT-3 combinatorial functions. In this section, timing characteristics are presented for a sample of the library. For more details, refer to the [Fusion](#), [IGLOO®/e](#), and [ProASIC3/E Macro Library Guide](#).

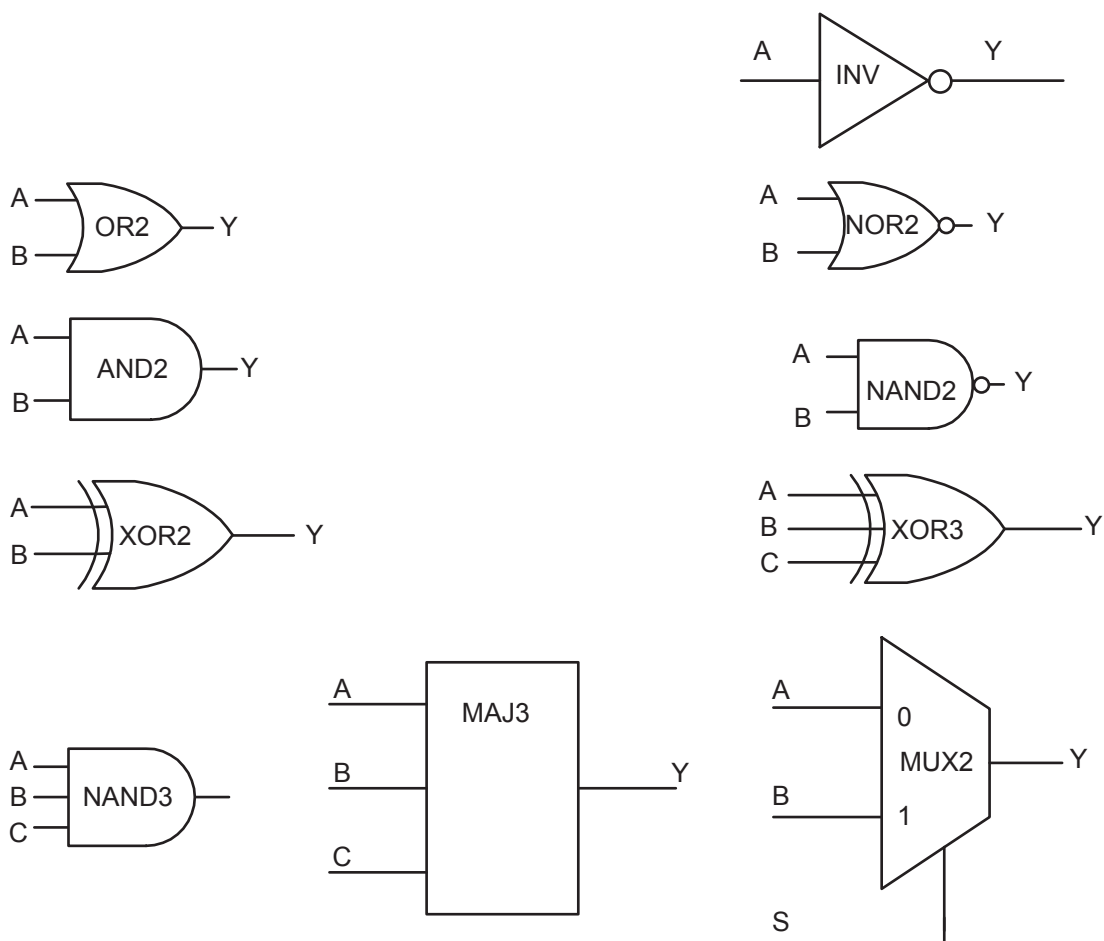


Figure 2-34 • Sample of Combinatorial Cells

Timing Characteristics

Table 2-99 • RAM4K9

Commercial-Case Conditions: $T_J = 70^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$

Parameter	Description	–2	–1	Std.	Units
t_{AS}	Address setup time	0.25	0.28	0.33	ns
t_{AH}	Address hold time	0.00	0.00	0.00	ns
t_{ENS}	REN, WEN setup time	0.14	0.16	0.19	ns
t_{ENH}	REN, WEN hold time	0.10	0.11	0.13	ns
t_{BKS}	BLK setup time	0.23	0.27	0.31	ns
t_{BKH}	BLK hold time	0.02	0.02	0.02	ns
t_{DS}	Input data (DIN) setup time	0.18	0.21	0.25	ns
t_{DH}	Input data (DIN) hold time	0.00	0.00	0.00	ns
t_{CKQ1}	Clock High to new data valid on DOUT (output retained, WMODE = 0)	1.79	2.03	2.39	ns
	Clock High to new data valid on DOUT (flow-through, WMODE = 1)	2.36	2.68	3.15	ns
t_{CKQ2}	Clock High to new data valid on DOUT (pipelined)	0.89	1.02	1.20	ns
t_{C2CWWL}^1	Address collision clk-to-clk delay for reliable write after write on same address—Applicable to Closing Edge	0.33	0.28	0.25	ns
t_{C2CWWH}^1	Address collision clk-to-clk delay for reliable write after write on same address—Applicable to Rising Edge	0.30	0.26	0.23	ns
t_{C2CRWH}^1	Address collision clk-to-clk delay for reliable read access after write on same address—Applicable to Opening Edge	0.45	0.38	0.34	ns
t_{C2CWRH}^1	Address collision clk-to-clk delay for reliable write access after read on same address—Applicable to Opening Edge	0.49	0.42	0.37	ns
t_{RSTBQ}	RESET Low to data out Low on DO (flow-through)	0.92	1.05	1.23	ns
	RESET Low to Data Out Low on DO (pipelined)	0.92	1.05	1.23	ns
$t_{REMRSTB}$	RESET removal	0.29	0.33	0.38	ns
$t_{RECRSTB}$	RESET recovery	1.50	1.71	2.01	ns
$t_{MPWRSTB}$	RESET minimum pulse width	0.21	0.24	0.29	ns
t_{CYC}	Clock cycle time	3.23	3.68	4.32	ns
F_{MAX}	Maximum frequency	310	272	231	MHz

Notes:

1. For more information, refer to the application note [Simultaneous Read-Write Operations in Dual-Port SRAM for Flash-Based cSoCs and FPGAs](#).
2. For specific junction temperature and voltage supply levels, refer to [Table 2-6 on page 2-5](#) for derating values.

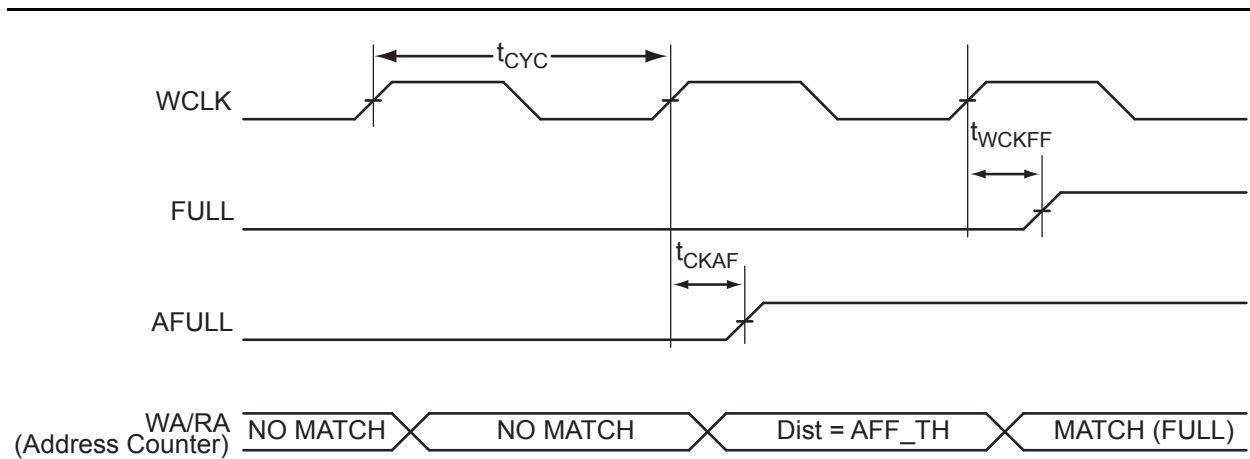


Figure 2-51 • FIFO FULL Flag and AFULL Flag Assertion

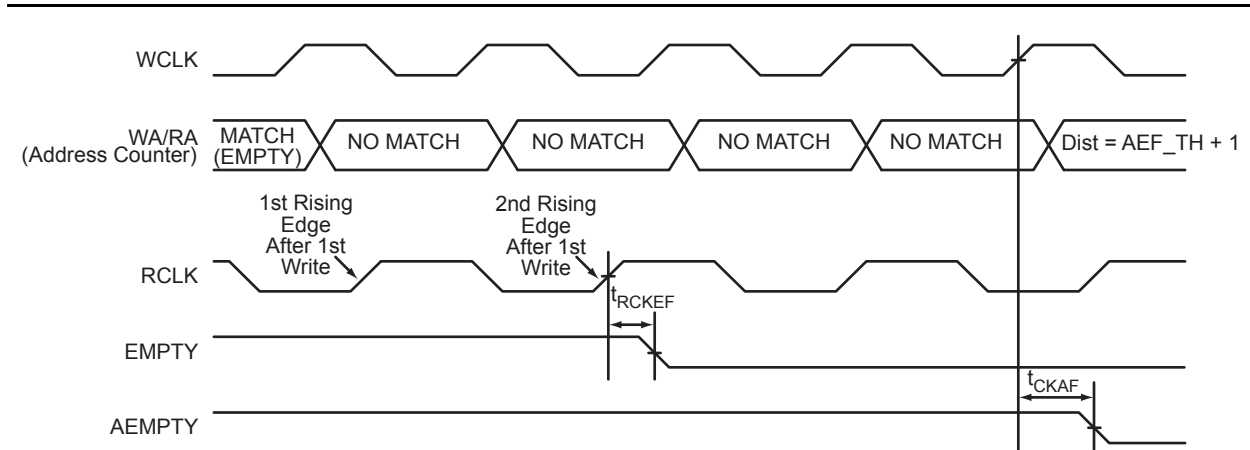


Figure 2-52 • FIFO EMPTY Flag and AEMPTY Flag Deassertion

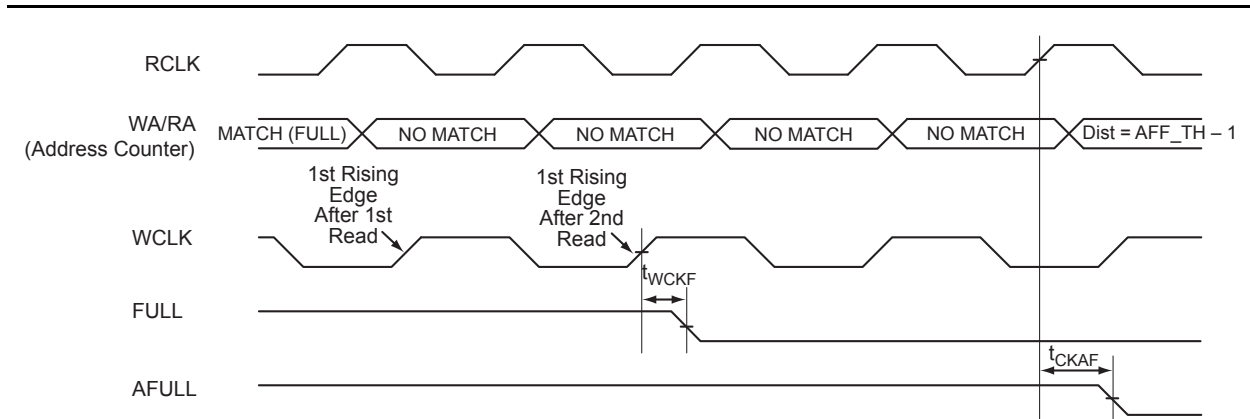


Figure 2-53 • FIFO FULL Flag and AFULL Flag Deassertion

Special Function Pins

NC

No Connect

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

DC

Do Not Connect

This pin should not be connected to any signals on the PCB. These pins should be left unconnected.

Packaging

Semiconductor technology is constantly shrinking in size while growing in capability and functional integration. To enable next-generation silicon technologies, semiconductor packages have also evolved to provide improved performance and flexibility.

Microsemi consistently delivers packages that provide the necessary mechanical and environmental protection to ensure consistent reliability and performance. Microsemi IC packaging technology efficiently supports high-density FPGAs with large-pin-count Ball Grid Arrays (BGAs), but is also flexible enough to accommodate stringent form factor requirements for Chip Scale Packaging (CSP). In addition, Microsemi offers a variety of packages designed to meet your most demanding application and economic requirements for today's embedded and mobile systems.

Related Documents

User's Guides

ProASIC3E FPGA Fabric User's Guide

http://www.microsemi.com/document-portal/doc_download/130883-proasic3e-fpga-fabric-user-s-guide

Packaging

The following documents provide packaging information and device selection for low power flash devices.

Product Catalog

http://www.microsemi.com/soc/documents/ProdCat_PIB.pdf

Lists devices currently recommended for new designs and the packages available for each member of the family. Use this document or the datasheet tables to determine the best package for your design, and which package drawing to use.

Package Mechanical Drawings

http://www.microsemi.com/document-portal/doc_download/131095-package-mechanical-drawings

This document contains the package mechanical drawings for all packages currently or previously supplied by Microsemi. Use the bookmarks to navigate to the package mechanical drawings.

Additional packaging materials: <http://www.microsemi.com/products/fpga-soc/solutions>.

FG256	
Pin Number	A3PE600 Function
P9	IO82PDB5V0
P10	IO76NDB4V1
P11	IO76PDB4V1
P12	VMV4
P13	TCK
P14	VPUMP
P15	TRST
P16	GDA0/IO67NDB3V1
R1	GEA1/IO102PDB6V0
R2	GEA0/IO102NDB6V0
R3	GNDQ
R4	GEC2/IO99PDB5V2
R5	IO95NPB5V1
R6	IO91NDB5V1
R7	IO91PDB5V1
R8	IO83NDB5V0
R9	IO83PDB5V0
R10	IO77NDB4V1
R11	IO77PDB4V1
R12	IO69NDB4V0
R13	GDB2/IO69PDB4V0
R14	TDI
R15	GNDQ
R16	TDO
T1	GND
T2	IO100NDB5V2
T3	GEB2/IO100PDB5V2
T4	IO99NDB5V2
T5	IO88NDB5V0
T6	IO88PDB5V0
T7	IO89NSB5V0
T8	IO80NSB4V1
T9	IO81NDB4V1
T10	IO81PDB4V1
T11	IO70NDB4V0
T12	GDC2/IO70PDB4V0

FG256	
Pin Number	A3PE600 Function
T13	IO68NDB4V0
T14	GDA2/IO68PDB4V0
T15	TMS
T16	GND

FG484	
Pin Number	A3PE600 Function
A1	GND
A2	GND
A3	VCCIB0
A4	IO06NDB0V1
A5	IO06PDB0V1
A6	IO08NDB0V1
A7	IO08PDB0V1
A8	IO11PDB0V1
A9	IO17PDB0V2
A10	IO18NDB0V2
A11	IO18PDB0V2
A12	IO22PDB1V0
A13	IO26PDB1V0
A14	IO29NDB1V1
A15	IO29PDB1V1
A16	IO31NDB1V1
A17	IO31PDB1V1
A18	IO32NDB1V1
A19	NC
A20	VCCIB1
A21	GND
A22	GND
AA1	GND
AA2	VCCIB6
AA3	NC
AA4	IO98PDB5V2
AA5	IO96NDB5V2
AA6	IO96PDB5V2
AA7	IO86NDB5V0
AA8	IO86PDB5V0
AA9	IO85PDB5V0
AA10	IO85NDB5V0
AA11	IO78PPB4V1
AA12	IO79NDB4V1
AA13	IO79PDB4V1
AA14	NC

FG484	
Pin Number	A3PE600 Function
AA15	NC
AA16	IO71NDB4V0
AA17	IO71PDB4V0
AA18	NC
AA19	NC
AA20	NC
AA21	VCCIB3
AA22	GND
AB1	GND
AB2	GND
AB3	VCCIB5
AB4	IO97NDB5V2
AB5	IO97PDB5V2
AB6	IO93NDB5V1
AB7	IO93PDB5V1
AB8	IO87NDB5V0
AB9	IO87PDB5V0
AB10	NC
AB11	NC
AB12	IO75NDB4V1
AB13	IO75PDB4V1
AB14	IO72NDB4V0
AB15	IO72PDB4V0
AB16	IO73NDB4V0
AB17	IO73PDB4V0
AB18	NC
AB19	NC
AB20	VCCIB4
AB21	GND
AB22	GND
B1	GND
B2	VCCIB7
B3	NC
B4	IO03NDB0V0
B5	IO03PDB0V0
B6	IO07NDB0V1

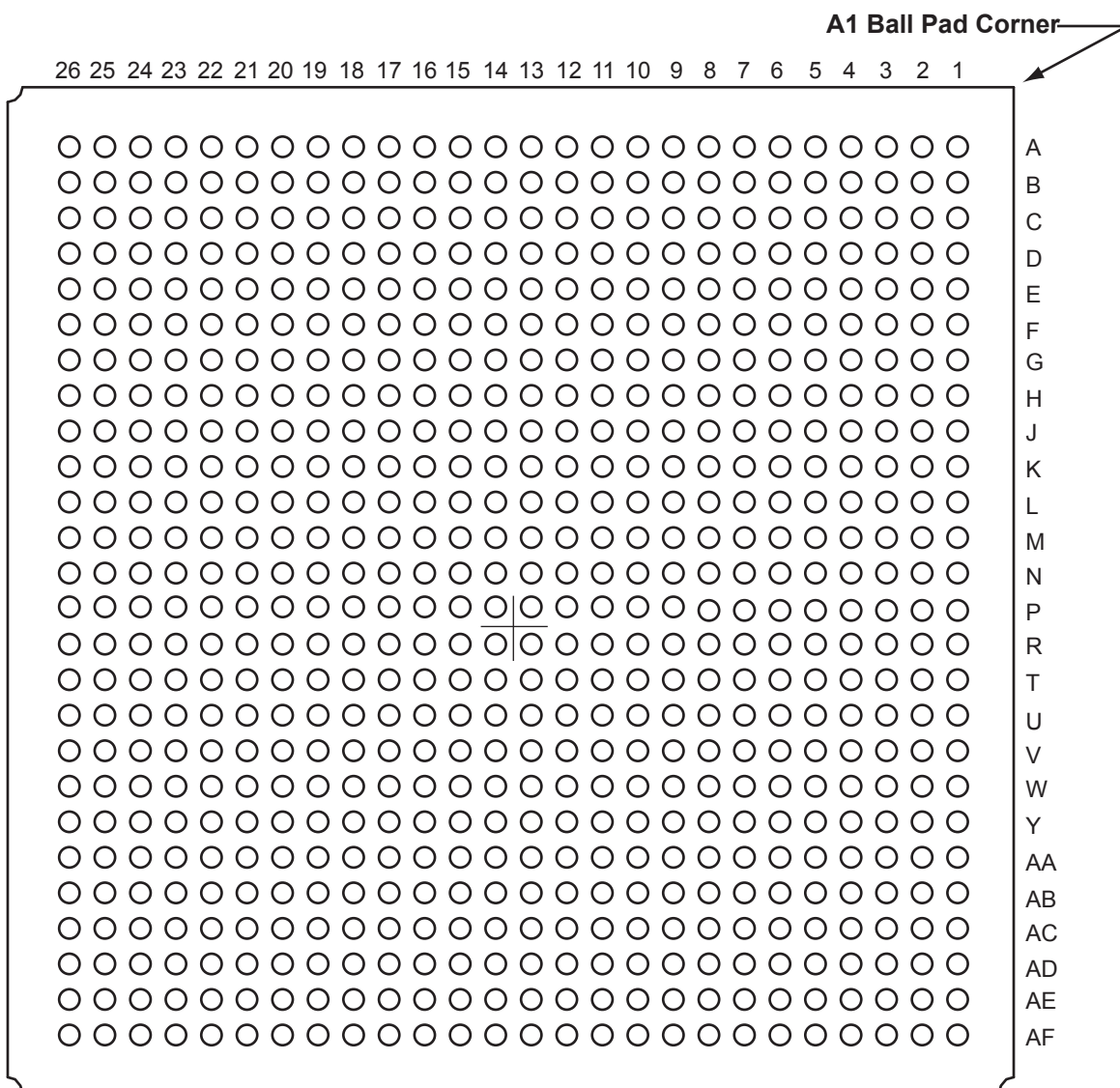
FG484	
Pin Number	A3PE600 Function
B7	IO07PDB0V1
B8	IO11NDB0V1
B9	IO17NDB0V2
B10	IO14PDB0V2
B11	IO19PDB0V2
B12	IO22NDB1V0
B13	IO26NDB1V0
B14	NC
B15	NC
B16	IO30NDB1V1
B17	IO30PDB1V1
B18	IO32PDB1V1
B19	NC
B20	NC
B21	VCCIB2
B22	GND
C1	VCCIB7
C2	NC
C3	NC
C4	NC
C5	GND
C6	IO04NDB0V0
C7	IO04PDB0V0
C8	VCC
C9	VCC
C10	IO14NDB0V2
C11	IO19NDB0V2
C12	NC
C13	NC
C14	VCC
C15	VCC
C16	NC
C17	NC
C18	GND
C19	NC
C20	NC

FG484	
Pin Number	A3PE1500 Function
C21	NC
C22	VCCIB2
D1	NC
D2	NC
D3	NC
D4	GND
D5	GAA0/IO00NDB0V0
D6	GAA1/IO00PDB0V0
D7	GAB0/IO01NDB0V0
D8	IO09PDB0V1
D9	IO13PDB0V1
D10	IO21PDB0V2
D11	IO31NDB0V3
D12	IO37NDB1V0
D13	IO37PDB1V0
D14	IO49NDB1V2
D15	IO49PDB1V2
D16	GBB1/IO56PDB1V3
D17	GBA0/IO57NDB1V3
D18	GBA1/IO57PDB1V3
D19	GND
D20	NC
D21	IO69PDB2V1
D22	NC
E1	NC
E2	IO218PPB7V3
E3	GND
E4	GAB2/IO220PDB7V3
E5	GAA2/IO221PDB7V3
E6	GNDQ
E7	GAB1/IO01PDB0V0
E8	IO09NDB0V1
E9	IO13NDB0V1
E10	IO21NDB0V2
E11	IO31PDB0V3
E12	IO35NDB1V0

FG484	
Pin Number	A3PE1500 Function
E13	IO41NDB1V1
E14	IO41PDB1V1
E15	GBC1/IO55PDB1V3
E16	GBB0/IO56NDB1V3
E17	GNDQ
E18	GBA2/IO58PDB2V0
E19	IO63NDB2V0
E20	GND
E21	IO69NDB2V1
E22	NC
F1	IO218NPB7V3
F2	IO216NDB7V3
F3	IO216PDB7V3
F4	IO220NDB7V3
F5	IO221NDB7V3
F6	VMV7
F7	VCCPLA
F8	GAC0/IO02NDB0V0
F9	GAC1/IO02PDB0V0
F10	IO23NDB0V2
F11	IO23PDB0V2
F12	IO35PDB1V0
F13	IO39NDB1V0
F14	IO45PDB1V1
F15	GBC0/IO55NDB1V3
F16	VCCPLB
F17	VMV2
F18	IO58NDB2V0
F19	IO63PDB2V0
F20	NC
F21	NC
F22	NC
G1	IO211NDB7V2
G2	IO211PDB7V2
G3	NC
G4	IO214PDB7V3

FG484	
Pin Number	A3PE1500 Function
G5	IO217PDB7V3
G6	GAC2/IO219PDB7V3
G7	VCOMPLA
G8	GNDQ
G9	IO19NDB0V2
G10	IO19PDB0V2
G11	IO25PDB0V3
G12	IO33PDB1V0
G13	IO39PDB1V0
G14	IO45NDB1V1
G15	GNDQ
G16	VCOMPLB
G17	GBB2/IO59PDB2V0
G18	IO62PDB2V0
G19	IO62NDB2V0
G20	IO71PDB2V2
G21	IO71NDB2V2
G22	NC
H1	IO209PSB7V2
H2	NC
H3	VCC
H4	IO214NDB7V3
H5	IO217NDB7V3
H6	IO219NDB7V3
H7	IO215PDB7V3
H8	VMV0
H9	VCCIB0
H10	VCCIB0
H11	IO25NDB0V3
H12	IO33NDB1V0
H13	VCCIB1
H14	VCCIB1
H15	VMV1
H16	GBC2/IO60PDB2V0
H17	IO59NDB2V0
H18	IO67NDB2V1

FG676



Note: This is the bottom view of the package.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.microsemi.com/products/fpga-soc/solutions>.

FG896	
Pin Number	A3PE3000 Function
AC21	IO164PDB4V1
AC22	IO162PPB4V1
AC23	GND
AC24	VCOMPLD
AC25	IO150NDB3V4
AC26	IO148NDB3V4
AC27	GDA1/IO153PDB3V4
AC28	IO145NDB3V3
AC29	IO143NDB3V3
AC30	IO137NDB3V2
AD1	GND
AD2	IO242NPB6V1
AD3	IO240NDB6V0
AD4	GEC0/IO236NDB6V0
AD5	VCCIB6
AD6	GNDQ
AD7	VCC
AD8	VMV5
AD9	VCCIB5
AD10	IO224PPB5V3
AD11	IO218NPB5V3
AD12	IO216PPB5V2
AD13	IO210PPB5V2
AD14	IO202PPB5V1
AD15	IO194PDB5V0
AD16	IO190PDB4V4
AD17	IO182NPB4V3
AD18	IO176NDB4V2
AD19	IO176PDB4V2
AD20	IO170PPB4V2
AD21	IO166PDB4V1
AD22	VCCIB4
AD23	TCK
AD24	VCC
AD25	TRST
AD26	VCCIB3

FG896	
Pin Number	A3PE3000 Function
AD27	GDA0/IO153NDB3V4
AD28	GDC0/IO151NDB3V4
AD29	GDC1/IO151PDB3V4
AD30	GND
AE1	IO242PPB6V1
AE2	VCC
AE3	IO239PDB6V0
AE4	IO239NDB6V0
AE5	VMV6
AE6	GND
AE7	GNDQ
AE8	IO230NDB5V4
AE9	IO224NPB5V3
AE10	IO214NPB5V2
AE11	IO212NDB5V2
AE12	IO212PDB5V2
AE13	IO202NPB5V1
AE14	IO200NDB5V0
AE15	IO196PDB5V0
AE16	IO190NDB4V4
AE17	IO184PDB4V3
AE18	IO184NDB4V3
AE19	IO172PDB4V2
AE20	IO172NDB4V2
AE21	IO166NDB4V1
AE22	IO160PDB4V0
AE23	GNDQ
AE24	VMV4
AE25	GND
AE26	GDB0/IO152NDB3V4
AE27	GDB1/IO152PDB3V4
AE28	VMV3
AE29	VCC
AE30	IO149PDB3V4
AF1	GND
AF2	IO238PPB6V0

FG896	
Pin Number	A3PE3000 Function
AF3	VCCIB6
AF4	IO220NPB5V3
AF5	VCC
AF6	IO228NDB5V4
AF7	VCCIB5
AF8	IO230PDB5V4
AF9	IO229NDB5V4
AF10	IO229PDB5V4
AF11	IO214PPB5V2
AF12	IO208NDB5V1
AF13	IO208PDB5V1
AF14	IO200PDB5V0
AF15	IO196NDB5V0
AF16	IO186NDB4V4
AF17	IO186PDB4V4
AF18	IO180NDB4V3
AF19	IO180PDB4V3
AF20	IO168NDB4V1
AF21	IO168PDB4V1
AF22	IO160NDB4V0
AF23	IO158NPB4V0
AF24	VCCIB4
AF25	IO154NPB4V0
AF26	VCC
AF27	TDO
AF28	VCCIB3
AF29	GNDQ
AF30	GND
AG1	IO238NPB6V0
AG2	VCC
AG3	IO232NPB5V4
AG4	GND
AG5	IO220PPB5V3
AG6	IO228PDB5V4
AG7	IO231NDB5V4
AG8	GEC2/IO231PDB5V4

FG896		FG896		FG896	
Pin Number	A3PE3000 Function	Pin Number	A3PE3000 Function	Pin Number	A3PE3000 Function
AG9	IO225NPB5V3	AH15	IO195NDB5V0	AJ21	IO173PDB4V2
AG10	IO223NPB5V3	AH16	IO185NDB4V3	AJ22	IO163NDB4V1
AG11	IO221PDB5V3	AH17	IO185PDB4V3	AJ23	IO163PDB4V1
AG12	IO221NDB5V3	AH18	IO181PDB4V3	AJ24	IO167NPB4V1
AG13	IO205NPB5V1	AH19	IO177NDB4V2	AJ25	VCC
AG14	IO199NDB5V0	AH20	IO171NPB4V2	AJ26	IO156NPB4V0
AG15	IO199PDB5V0	AH21	IO165PPB4V1	AJ27	VCC
AG16	IO187NDB4V4	AH22	IO161PPB4V0	AJ28	TMS
AG17	IO187PDB4V4	AH23	IO157NDB4V0	AJ29	GND
AG18	IO181NDB4V3	AH24	IO157PDB4V0	AJ30	GND
AG19	IO171PPB4V2	AH25	IO155NDB4V0	AK2	GND
AG20	IO165NPB4V1	AH26	VCCIB4	AK3	GND
AG21	IO161NPB4V0	AH27	TDI	AK4	IO217PPB5V2
AG22	IO159NDB4V0	AH28	VCC	AK5	GND
AG23	IO159PDB4V0	AH29	VPUMP	AK6	IO215PPB5V2
AG24	IO158PPB4V0	AH30	GND	AK7	GND
AG25	GDB2/IO155PDB4V0	AJ1	GND	AK8	IO207NDB5V1
AG26	GDA2/IO154PPB4V0	AJ2	GND	AK9	IO207PDB5V1
AG27	GND	AJ3	GEA2/IO233PPB5V4	AK10	IO201NDB5V0
AG28	VJTAG	AJ4	VCC	AK11	IO201PDB5V0
AG29	VCC	AJ5	IO217NPB5V2	AK12	IO193NDB4V4
AG30	IO149NDB3V4	AJ6	VCC	AK13	IO193PDB4V4
AH1	GND	AJ7	IO215NPB5V2	AK14	IO197PDB5V0
AH2	IO233NPB5V4	AJ8	IO213NDB5V2	AK15	IO191NDB4V4
AH3	VCC	AJ9	IO213PDB5V2	AK16	IO191PDB4V4
AH4	GEB2/IO232PPB5V4	AJ10	IO209NDB5V1	AK17	IO189NDB4V4
AH5	VCCIB5	AJ11	IO209PDB5V1	AK18	IO189PDB4V4
AH6	IO219NDB5V3	AJ12	IO203NDB5V1	AK19	IO179PPB4V3
AH7	IO219PDB5V3	AJ13	IO203PDB5V1	AK20	IO175NDB4V2
AH8	IO227NDB5V4	AJ14	IO197NDB5V0	AK21	IO175PDB4V2
AH9	IO227PDB5V4	AJ15	IO195PDB5V0	AK22	IO169NDB4V1
AH10	IO225PPB5V3	AJ16	IO183NDB4V3	AK23	IO169PDB4V1
AH11	IO223PPB5V3	AJ17	IO183PDB4V3	AK24	GND
AH12	IO211NDB5V2	AJ18	IO179NPB4V3	AK25	IO167PPB4V1
AH13	IO211PDB5V2	AJ19	IO177PDB4V2	AK26	GND
AH14	IO205PPB5V1	AJ20	IO173NDB4V2	AK27	GDC2/IO156PPB4V0

Revision	Changes	Page
Advance v0.5 (continued)	The "I/O User Input/Output" pin description was updated to include information on what happens when the pin is unused.	2-50
	The "JTAG Pins" section was updated to include information on what happens when the pin is unused.	2-51
	The "Programming" section was updated to include information concerning serialization.	2-53
	The "JTAG 1532" section was updated to include SAMPLE/PRELOAD information.	2-54
	The "DC and Switching Characteristics" chapter was updated with new information.	Starting on page 3-1
	Table 3-6 was updated.	3-5
	In Table 3-10, PAC4 was updated.	3-8
	Table 3-19 was updated.	3-20
	The note in Table 3-24 was updated.	3-23
	All Timing Characteristics tables were updated from LVTTTL to Register Delays	3-26 to 3-64
	The Timing Characteristics for RAM4K9, RAM512X18, and FIFO were updated.	3-74 to 3-79
	F _{TCKMAX} was updated in Table 3-98.	3-80
Advance v0.4 (October 2005)	The "Packaging Tables" table was updated.	ii
Advance v0.3	Figure 2-11 was updated.	2-9
	The "Clock Resources (VersaNets)" section was updated.	2-9
	The "VersaNet Global Networks and Spine Access" section was updated.	2-9
	The "PLL Macro" section was updated.	2-15
	Figure 2-27 was updated.	2-28
	Figure 2-20 was updated.	2-19
	Table 2-5 was updated.	2-25
	Table 2-6 was updated.	2-25
	The "FIFO Flag Usage Considerations" section was updated.	2-27
	Table 2-33 was updated.	2-51
	Figure 2-24 was updated.	2-31
	The "Cold-Sparing Support" section is new.	2-34
	Table 2-45 was updated.	2-64
	Table 2-48 was updated.	2-81
	Pin descriptions in the "JTAG Pins" section were updated.	2-51
	The "Pin Descriptions" section was updated.	2-50
	Table 3-7 was updated.	3-6



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